

Notice of References Cited	Application/Control No. 10/039,383	Applicant(s)/Patent Under Reexamination CHU ET AL.	
	Examiner S. Devi, Ph.D.	Art Unit 1645	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,846,477	01-2005	Keich et al.	424/9.1
*	B	US-5,695,769	12-1997	Frantz et al.	424/255.1
*	C	US-6,585,981	07-2003	Pijoan, Carlos	424/264.1
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 02/10343 ✓	02-2002	PCT	Pijoan	
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Martinon et al. In: Proc. 15th IPVS Congress. (Ed) Stanley Done et al. Birmingham, England, 5-9 July 1998, page 284. ✓
	V	Reynaud et al. In: Proc. 15th IPVS Congress. (Ed) Stanley Done et al. Birmingham, England, 5-9 July 1998, page 150. ✓
	W	Charlier et al. In: Proc. 16th IPVS Congress. (Ed) Cargill et al. Melbourne, Australia, 17-20 September 2000, page 501. ✓
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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Aug. 05